

Glossary of Terms

The following glossary is a list of terms commonly used in the trade in Alberta and elsewhere in Canada. Individuals preparing for examinations should be familiar with these terms and how they are used in the context of the trade.

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|----------------------------|-------------------------------|--------------------------|
| Acceptable high frequency | Communications protocol | I LEC's |
| Alpha current relationship | Conductance | Impedance |
| AMI | Convertor | Impedance mismatches |
| Amplitude | Coulomb | Inductance |
| Amplitude modulation | D flip flops | Inductive reactance |
| Asynchronous | Data trapping | Insertion loss |
| Attenuation | Dead zone | Interconnecting |
| Attenuation | Decay | Invertor |
| Back EMF | Diamagnetic | ISO/IEC cable tests |
| Bandwidth | Dielectric | IXC's |
| Bandwidth budget | Diode clipper | J-K flip flops |
| Base bias | Diode curve | Karnaugh mapping |
| Base driven amplifiers | Duty cycle | Klystron |
| Baud rate | Dynamic resistance | Kirchhoff's Laws |
| Beta current relationship | Echo return loss | LAN's |
| Binary number system | Elastic buffering | LATA's |
| Bipolar | Electrolytic | Leading edge |
| B-ISDN | Electromagnetic spectra | Leakage current |
| Blocking (damming) | Emitter bias | Loading schemes |
| Bonding | Emitter driven amplifiers | Loss budget |
| Boolean algebra | Encoding signals | Lower cut-off frequency |
| Breakdown voltage | Exponential function | circuits |
| Buffering | Fall time | Manchester code |
| Build out capacitors | Fault tolerance | Mark length |
| Cable pressurization | Ferromagnetic | Mark/space ratio |
| CAN's | Field Effect Transistor (FET) | Modem protocols |
| Capacitive reactances | FO certification tests | MSDS |
| Capacitors | Forward bias | MUDD |
| Cartesian coordinates | Fourier analysis | Multi-drop configuration |
| Cel-peth | Frequency domain | Multiplexing |
| Cel-seal | Frequency domain | Multiplexing |
| Characteristic Impedance | characteristics | Nand gate S-R circuits |
| Chokes | Frequency spectrum | NAND gates |
| CLEC's | Frequency synthesis | Natural logarithm |
| Clocked S-R circuits | Fresnel reflection | Network interface device |
| Clocking | Harmonic analysis | (NID) |
| Coaxial | Harmonic nulling factor | NTSC |
| Coil spacing | Hexadecimal number system | Numerical aperture |
| Collector feedback bias | Hybrid loss | Nyquist Theore |

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| Octal number system | Self-inductance |
| Ohm's Law | Semiconductor |
| Oscillator | Semiconductors |
| OTDR testing | Shannon's Communication Theory |
| PABX | Sine wave |
| PAL | Singing |
| Paramagnetic | Sinusoidal |
| Pasp | Shield bonding |
| PBX | Snell's Law |
| PCM cables | SONET |
| PCN | Space width |
| Peak inverse voltage | Spark gap |
| Phase | Spark gap protection |
| Phasor | Square wave distortion |
| Pic alpeth | Stal-cel |
| Pic F | Stalpeth |
| Pic pap | Standing Waves |
| Pic S | STP characteristics |
| Plesiochronous digital hierarchy | Super position theorem |
| PN Junction | Synchronization |
| Point-to-point communications | Synchronous |
| Polar coordinates | Synchronous digital hierarchy |
| Polarization | TDM multiplexers |
| POP's | Telephony |
| Precipitation static | Thevenin's theorem |
| Pressure (flash) testing | TIA/EIA-606 standard |
| Propagation | Tilt |
| Propagation constant | Time division multiplexing (TDM) |
| Pulse amplitude | Time domain characteristics |
| Pulse duration | Time period |
| Pulse repetition frequency | Trailing edge |
| Pulse repetition rate | Trans-hybrid loss |
| Pulse width | Transient current flow |
| Pulses per second | Unipolar |
| Punch-down block | Upper cut-off frequency |
| Quantizing | UTP characteristics |
| Quantization noise | Vestigial sideband |
| Radiation resistance | WAN's |
| Reactance | Wave shape |
| Rectifier diode | Wave shaping |
| Resistance | Wien bridge |
| Resistors | Zener diodes |
| Resonance | |
| Resonant lines | |
| Return loss | |
| Return loss concepts | |
| Reverse bias | |
| Reverse resistance | |
| Rise time | |
| Saturation voltage | |
| ScTP characteristics | |
| SECAM | |